

[Fig. 1]

S0 sets the entered slice level to a predetermined one of S_k

S1 measures jitter to produce a measured jitter
value A

5 S2 increments the slice level in steps of S_i

S3 measures the jitter and produces a measured
jitter value B

S5 stops the incrementing of the slice level, and measures
jitter quantity and produces a measured jitter value C

10 S6 decrements the slice level in steps of another fixed
quantity S_d ($< S_i$)

S7 measures the jitter and produces a measured jitter value

D

[Fig. 2]

- A jitter
- B reference slice level
- C slice level

5

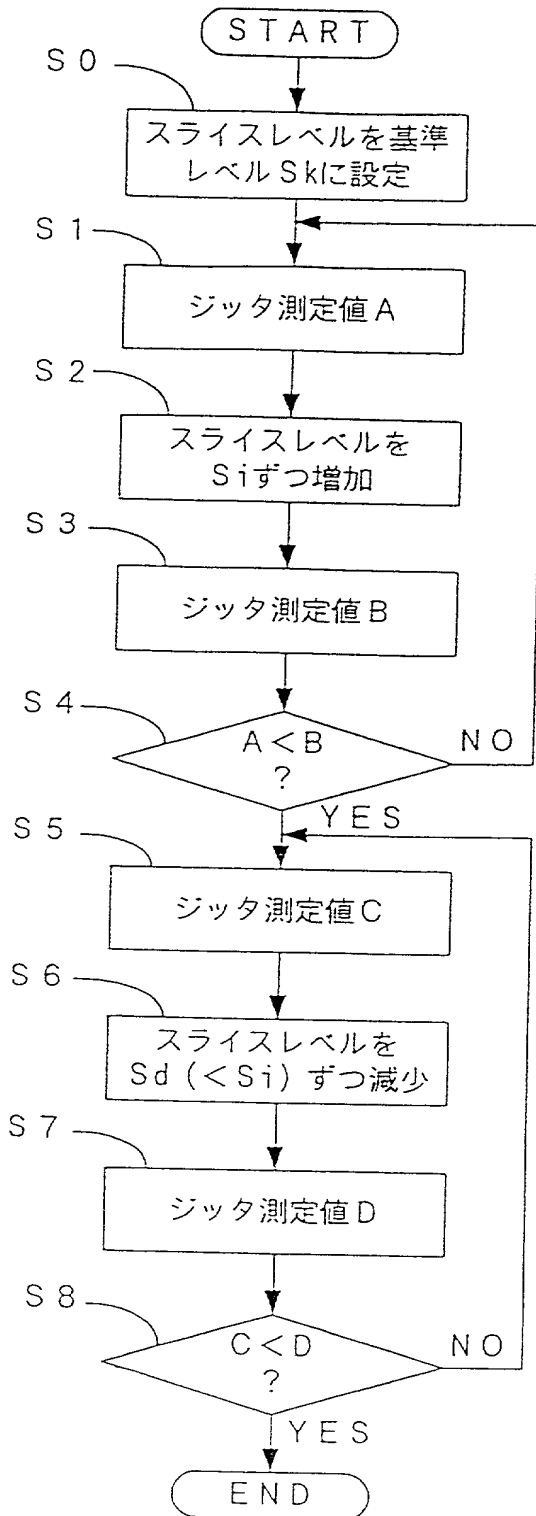
[Fig. 4]

- A RF signal
- B binarized signal
- 10 4 RF amplifier
- 5 Decoder
- 6 Microcomputer

15 [Fig. 5]

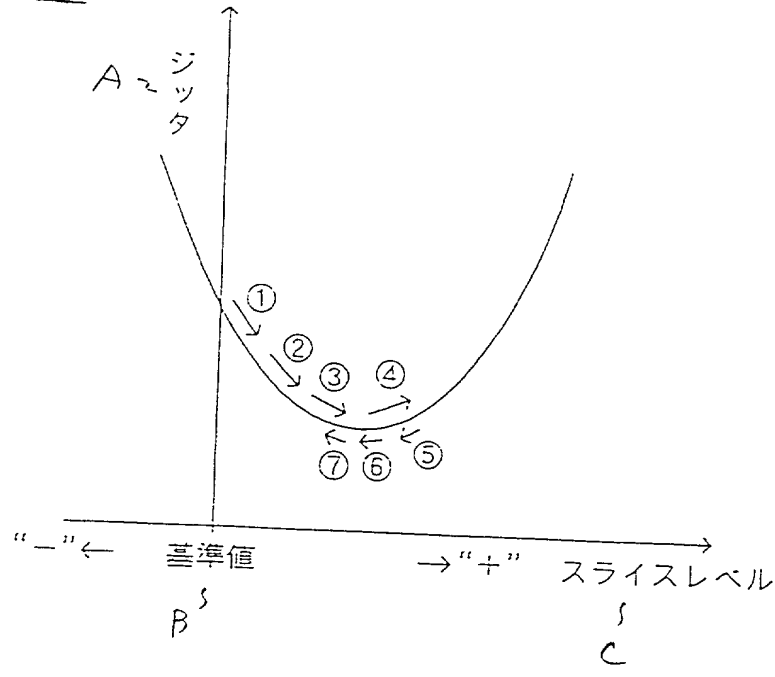
- A RF signal
- B binarized signal

Fig. 1



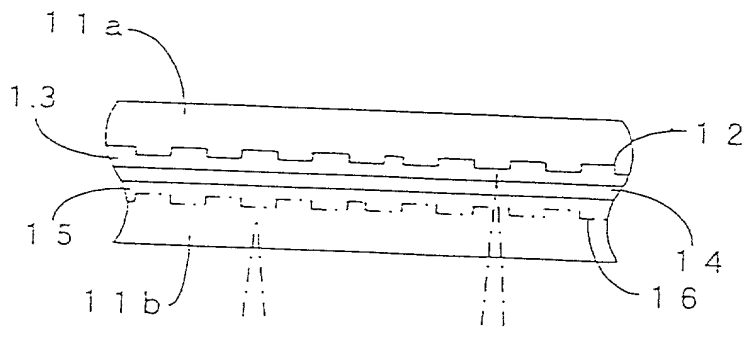
〔図2〕

Fig. 2

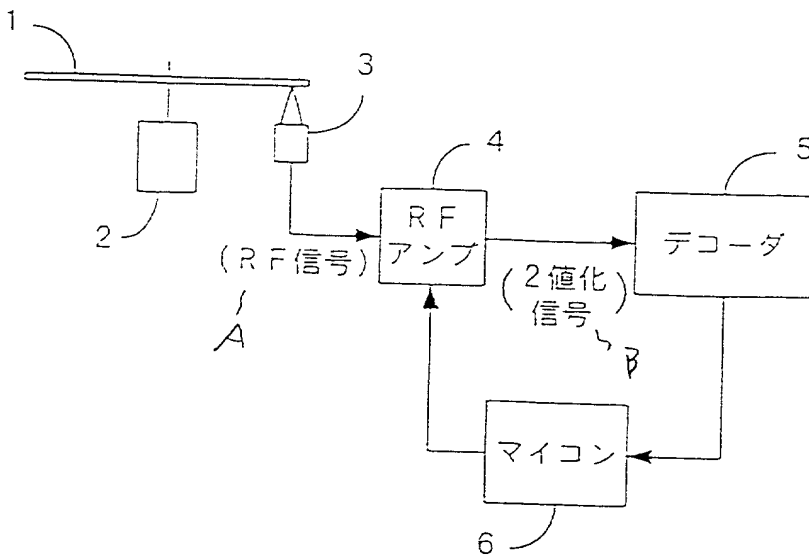


〔図3〕

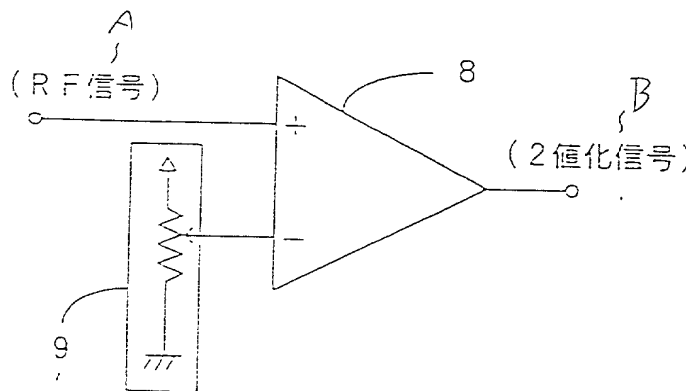
Fig. 3



(図4) Fig. 4



(図5) Fig. 5



(START)

sets the entered slice level to a predetermined one of 52

store A

increments the slice level in steps of Si

store B

leave A, delete B, store C

increment the slice level

delete A, leave B, store C

increment the slice level

leave B, delete C, store D

increment the slice level

delete B, leave C, store D

increment the slice level

set D to be the best value

(END)

Y

N

Y

N

Y

N

Y

N

Y

N

Y

N

Y

N

Y

N

Y

N

Y

N

Y

N

Y

N

Y

N

Y

Fig. 6

(A, B, C, D : jitter)

